

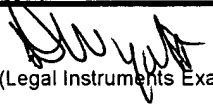


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/750,629	WANG ET AL.	
	Examiner	Art Unit	
	Kim T. Huynh	2112	

ISSUE CLASSIFICATION										
ORIGINAL					CROSS REFERENCE(S)					
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
710		317			710	316				
INTERNATIONAL CLASSIFICATION					370	360				
G	0	6	F	13/00						
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Kim T. Huynh 11/2/05 (Assistant Examiner) (Date)					 REHANA PERVEEN SUPERVISORY PATENT EXAMINER			Total Claims Allowed: 20		
 (Legal Instruments Examiner) (Date)					(Primary Examiner)			O.G. Print Claim(s) 21		O.G. Print Fig. 5

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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